

<b>Notice of References Cited</b>	Application/Control No. 10/656,652	Applicant(s)/Patent Under Reexamination CHALUPSKY ET AL.	
	Examiner Brian P. Whipple	Art Unit 2152	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0003296 A1	01-2004	Robert et al.	713/300
*	B	US-6,298,042 B1	10-2001	Murase et al.	370/235
*	C	US-5,881,240 A	03-1999	Asano, Yuji	709/233
*	D	US-6,789,130 B1	09-2004	Benayoun et al.	709/250
*	E	US-6,026,494 A	02-2000	Foster, Jay Arnold	713/320
*	F	US-2004/0117674 A1	06-2004	Gutman et al.	713/300
*	G	US-6,529,957 B1	03-2003	Joergensen, Thomas Kirkegaard	709/233
*	H	US-7,171,483 B2	01-2007	Klein, Paul F.	709/232
*	I	US-2003/0023665 A1	01-2003	Matsunami et al.	709/201
*	J	US-6,389,476 B1	05-2002	Olnowich, Howard Thomas	709/233
*	K	US-6,665,810 B1	12-2003	Sakai, Yasushi	713/600
*	L	US-7,054,947 B2	05-2006	Yun, Yeou-sun	709/233
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.